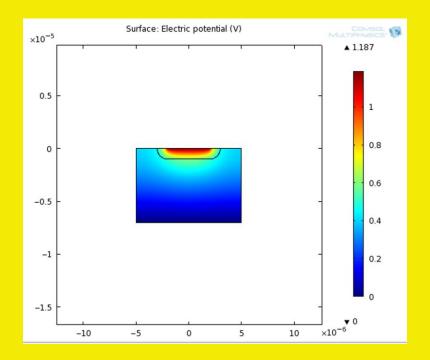
Modeling PIN Photodiodes

Roger W. Pryor, Ph.D., VP Research Pryor Knowledge Systems, Inc.



PIN Photodiode Modeling

This paper presents a new AC/DC Conduction Current Module Model of a PIN Photodiode using COMSOL Multiphysics 4.0a and SPICE



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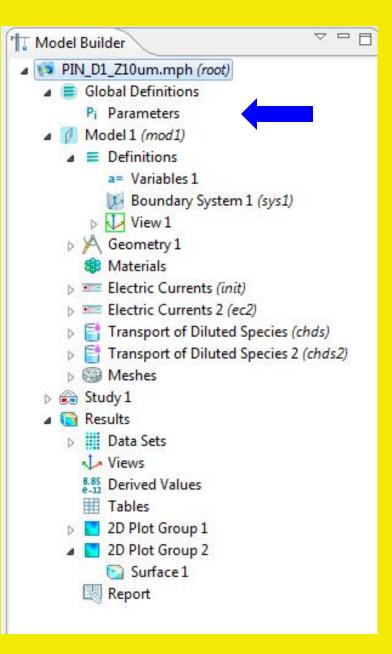
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- 9. Light Generated Carrier Pairs (Electrons(-), Holes(+))

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Building the PIN Photodiode Model Model Builder Chart Model 1



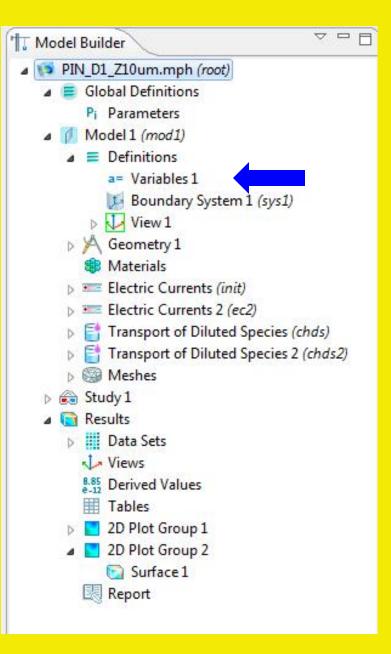
Building the PIN Photodiode Model

Parameters

Parameter	Value	Description				
q	1.602e-19[C]	Elementary charge				
Т	300[K]	Room temperature				
k	1.38e-23[J/K]	Boltzmann's constant				
epsilonr	11.8	Rel. permittivity for Si				
ni	1.46e10[1/cm^3]	Intrinsic concentration for Si				
mun	800[cm^2/(V*s)]	Electron mobility for Si				
mup	200[cm^2/(V*s)]	Hole mobility for Si				
Dn	k*T/q*mun	Electron diffusivity				
Dp	k*T/q*mup	Hole diffusivity				
taun	0.1[us]	Electron life time				
taup	0.1[us]	Hole life time				
с	q/(k*T)	Reciprocal thermal voltage				
y1	7[um]	Diode dimension				
x1	10[um]	Diode dimension				
ju	1[um]	Junction depth				
ac	4[um]	Anode dimension				
NApmax	1e17[1/cm^3]	Maximum p-type doping				
NDn	1e15[1/cm^3]	Drift layer n-type doping				
NDnmax	1e17[1/cm^3]	Maximum n-type doping				
ch	ju/sqrt(log(NApmax/NDn))	Doping fall-off constant				
Va	0[V]	Applied voltage				
Vt	k*T/q	Thermal voltage				
Vpsi0	0[V]	Initialization voltage				

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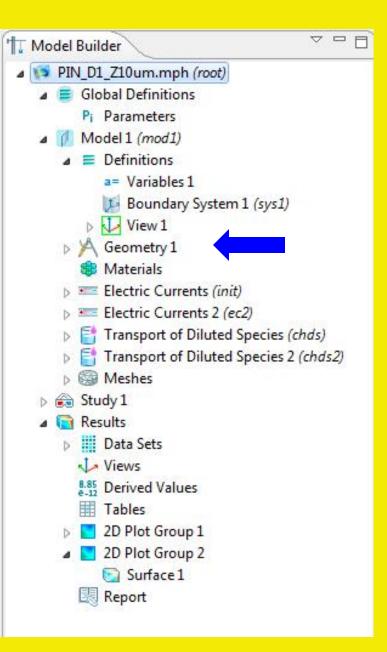
Building the PIN Photodiode Model

Variables

Variable	Expression	Description
Ν	NDn+NDnmax*exp(-((y+y1)/ch)^2)-NApmax*exp(-	Doping
	$(y/ch)^{2}*((abs(x) < ac/2)+(abs(x) > = ac/2)*exp(-((abs(x)-ac/2)/ch)^{2}))$	concentration
n_init	$(abs(N)/2+sqrt(N^2/4+ni^2))*(N \ge 0)+ni^2/(abs(N)/2+sqrt(N^2/4+ni^2))*(N < 0)$	Charge neutrality
		electron
		concentration
p_init	$(abs(N)/2+sqrt(N^2/4+ni^2))*(N<0)+ni^2/(abs(N)/2+sqrt(N^2/4+ni^2))*(N>=0)$	Charge neutrality
		hole concentration
V_psi_init	$1/c*(-\log(p_{init/ni})*(N<0)+\log(n_{init/ni})*(N>=0))$	Charge neutrality
		voltage
RSRH	$(cn[1/mol]*cp[1/mol]-ni^2)/(taup*(cn[1/mol]+ni)+taun*(cp[1/mol]+ni))$	Recombination
		term
sigma_si	q*(cn[1/mol]*mun+cp[1/mol]*mup)	Conductivity of
		doped silicon
cn0	$ni*exp(-(V_psi0/Vt))$	Thermal Eq
		electron
		concentration
cp0	$ni*exp(-(V_psi0/Vt))$	Thermal Eq hole
		concentration
sigma_sip	q*cp0*mup	P domain
		conductivity
sigma_sin	q*cn0*mun	N domain
		conductivity

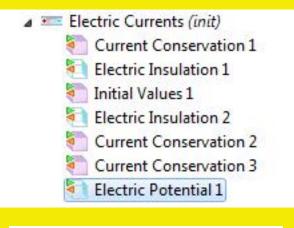
Building the PIN Photodiode Model PIN Photodiode Geometry

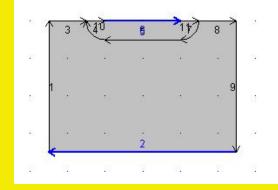
	x10 ⁻⁵												
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0.4	- 22	3	28	85	14	11	3	78	97	-	12	73	53525
0.2			52	<u>.</u>	8	100	1	52		8	10		900- 5 0)
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-1		8			a	si.	a.	s)	×	a	6	19	
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			12	-		0		12			1.		
	<mark>-1.2</mark>	-1	-0.8	-0.6	-0.4	-0.2	0	0.2	0.4	0.6	0.8	1	1.2 x10 ⁻⁵

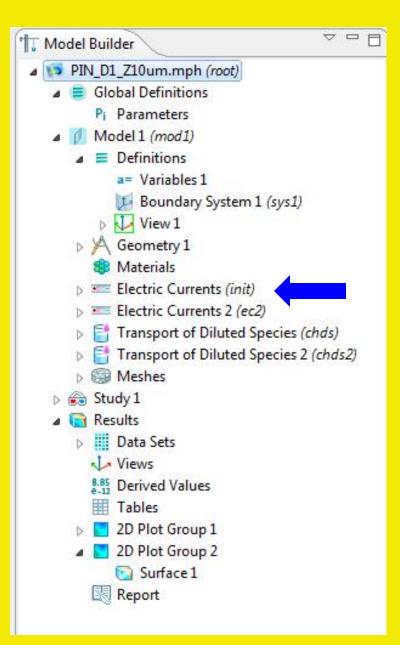


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Building the PIN Photodiode Model PIN Photodiode Initialization

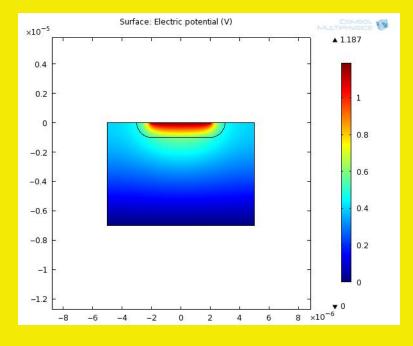


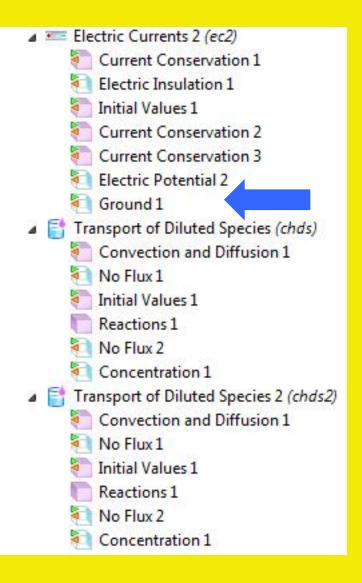




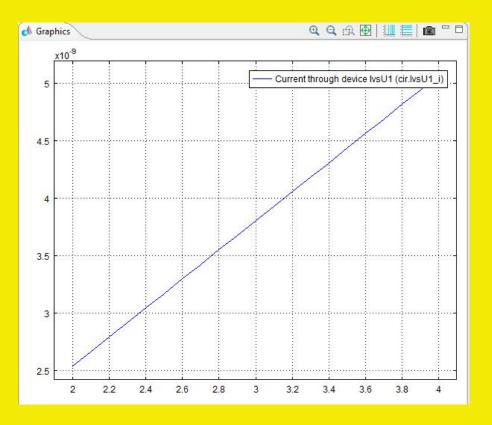
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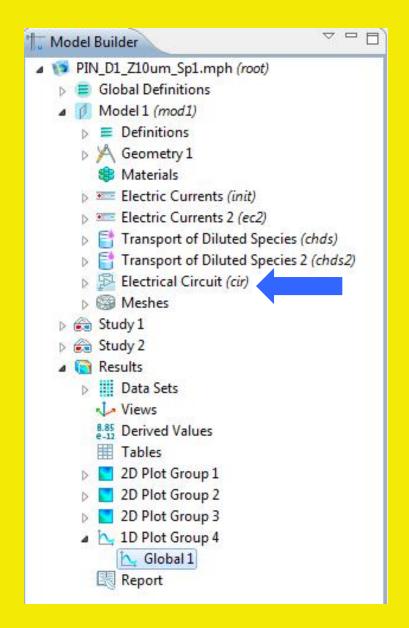
Building the PIN Photodiode Model PIN Photodiode Calculation





Building the PIN Photodiode Model PIN Photodiode Calculation & SPICE





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PIN Photodiode Model Conclusions

- 1. AC/DC Conduction Current Semiconductor Models can be built in COMSOL Multiphysics 4.0a, using sufficient care.
- 2. Such Semiconductor Models can be used with SPICE, with proper boundary conditions.

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Thank You!

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